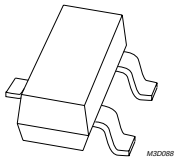


SI2302DS

N-channel enhancement mode field-effect transistor

Rev. 02 — 20 November 2001 **Product data**

1. Description

N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS™[1] technology.

Product availability:

SI2302DS in SOT23.

2. Features

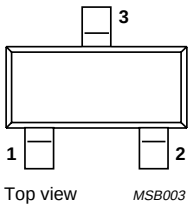
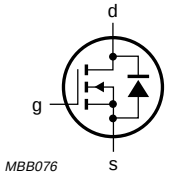
- TrenchMOS™ technology
- Very fast switching
- Logic level compatible
- Subminiature surface mount package.

3. Applications

- Battery management
- High speed switch
- Low power DC to DC converter.

4. Pinning information

Table 1: Pinning - SOT23, simplified outline and symbol

Pin	Description	Simplified outline	Symbol
1	gate (g)		
2	source (s)		
3	drain (d)		

SOT23

1. TrenchMOS is a trademark of Koninklijke Philips Electronics N.V.

5. Quick reference data

Table 2: Quick reference data

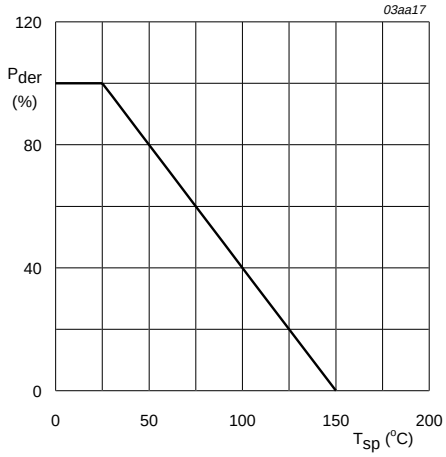
Symbol	Parameter	Conditions	Typ	Max	Unit
V_{DS}	drain-source voltage (DC)	T_j = 25 to 150 °C	–	20	V
I_D	drain current (DC)	T_{sp} = 25 °C; V_{GS} = 4.5 V	–	2.5	A
P_{tot}	total power dissipation	T_{sp} = 25 °C	–	0.83	W
T_j	junction temperature		–	150	°C
R_{DSon}	drain-source on-state resistance	V_{GS} = 4.5 V; I_D = 3.6 A	56	85	mΩ
		V_{GS} = 2.5 V; I_D = 3.1 A	77	115	mΩ

6. Limiting values

Table 3: Limiting values

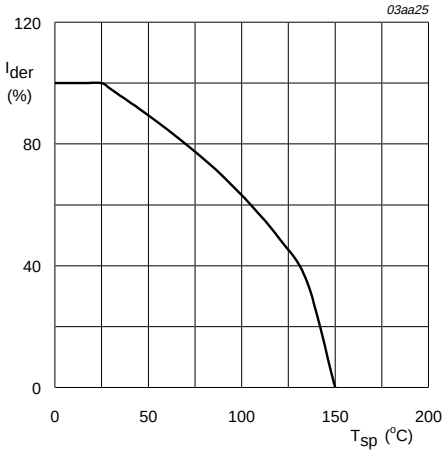
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage (DC)	T_j = 25 to 150 °C	–	20	V
V_{GS}	gate-source voltage (DC)		–	±8	V
I_D	drain current (DC)	T_{sp} = 25 °C; V_{GS} = 4.5 V; Figure 2 and 3	–	2.5	A
		T_{sp} = 70 °C; V_{GS} = 4.5 V; Figure 2	–	2	A
I_{DM}	peak drain current	T_{sp} = 25 °C; pulsed; $t_p \leq 10$ µs; Figure 3	–	10	A
P_{tot}	total power dissipation	T_{sp} = 25 °C; Figure 1	–	0.83	W
T_{stg}	storage temperature		–65	+150	°C
T_j	operating junction temperature		–65	+150	°C
Source-drain diode					
I_S	source (diode forward) current (DC)	T_{sp} = 25 °C	–	0.7	A



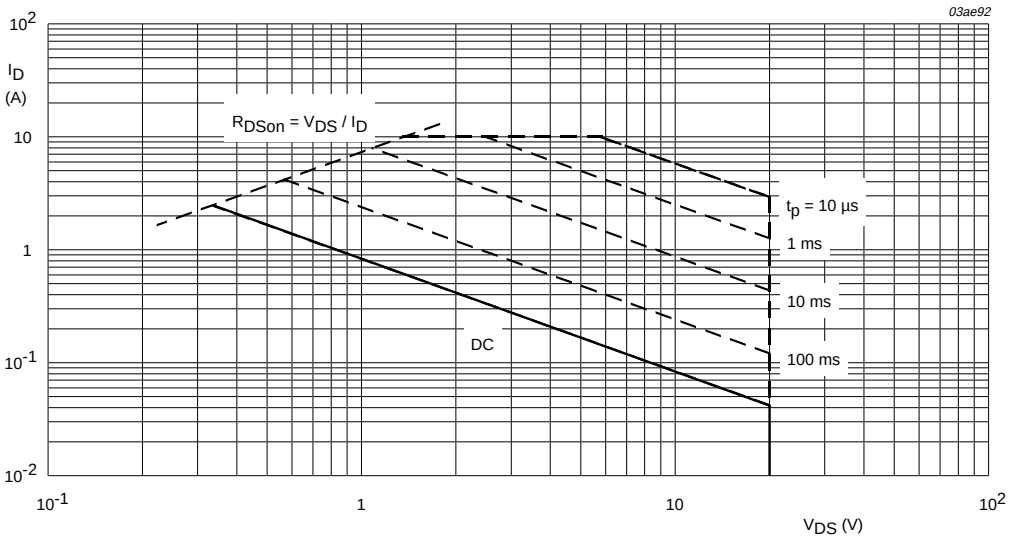
$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized total power dissipation as a function of solder point temperature.



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of solder point temperature.



T_{sp} = 25 °C; I_{DM} is single pulse.

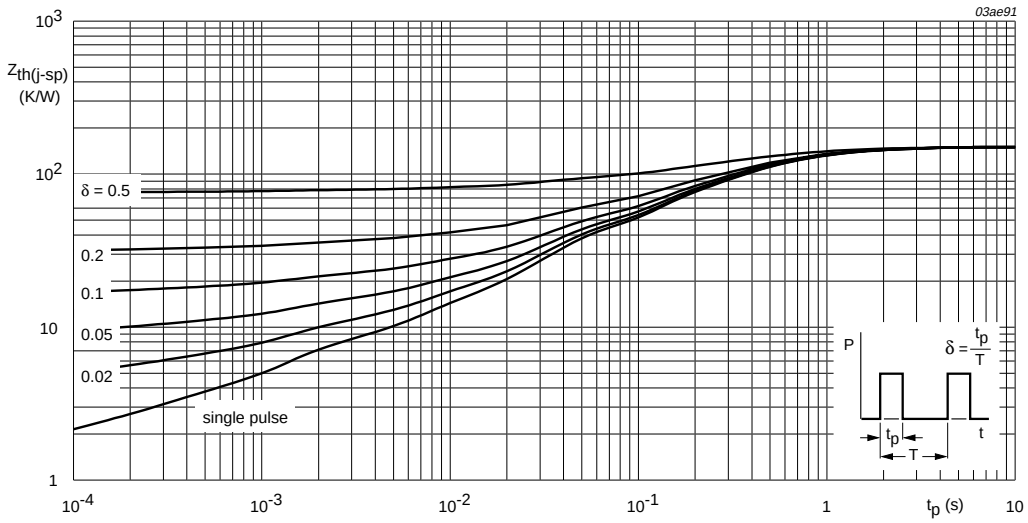
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Value	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	mounted on a metal clad substrate; Figure 4	150	K/W

7.1 Transient thermal impedance



T_{sp} = 25 °C

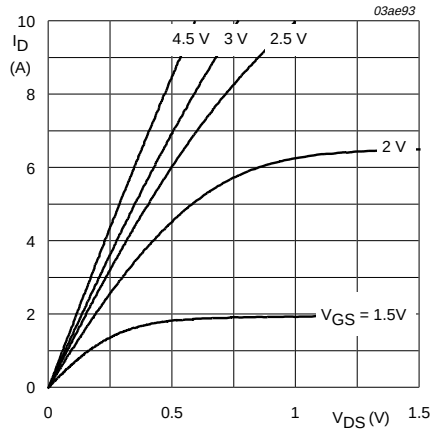
Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration.

8. Characteristics

Table 5: Characteristics

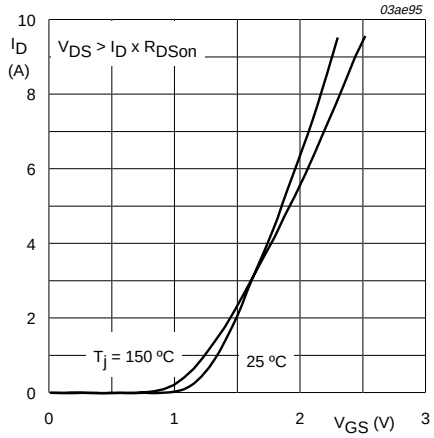
T_j = 25 °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	I_D = 10 μA; V_{GS} = 0 V	20	–	–	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS}; Figure 9	0.65	–	–	V
I_{DSS}	drain-source leakage current	V_{DS} = 20 V; V_{GS} = 0 V				
		T_j = 25 °C	–	0.01	1.0	μA
		T_j = 55 °C	–	–	10	μA
I_{GSS}	gate-source leakage current	V_{GS} = ±8 V; V_{DS} = 0 V	–	10	100	nA
R_{DSon}	drain-source on-state resistance	V_{GS} = 4.5 V; I_D = 3.6 A; Figure 7 and 8	–	56	85	mΩ
		V_{GS} = 2.5 V; I_D = 3.1 A; Figure 7 and 8	–	77	115	mΩ
Dynamic characteristics						
g_{fs}	forward transconductance	V_{DS} = 5 V; I_D = 3.6 A	–	8	–	S
$Q_{g(tot)}$	total gate charge	V_{DD} = 10 V; V_{GS} = 4.5 V; I_D = 3.6 A; Figure 13	–	5.4	10	nC
Q_{gs}	gate-source charge		–	0.65	–	nC
Q_{gd}	gate-drain (Miller) charge		–	1.6	–	nC
C_{iss}	input capacitance	V_{GS} = 0 V; V_{DS} = 10 V; f = 1 MHz; Figure 11	–	230	–	pF
C_{oss}	output capacitance		–	125	–	pF
C_{rss}	reverse transfer capacitance		–	80	–	pF
$t_{d(on)}$	turn-on delay time	V_{DD} = 10 V; R_L = 5.5 Ω; V_{GS} = 4.5 V; R_G = 6 Ω	–	12	20	ns
t_r	rise time		–	23	35	ns
$t_{d(off)}$	turn-off delay time		–	50	100	ns
t_f	fall time		–	34	50	ns
Source-drain diode						
V_{SD}	source-drain (diode forward) voltage	I_S = 1.6 A; V_{GS} = 0 V; Figure 12	–	0.8	1.2	V



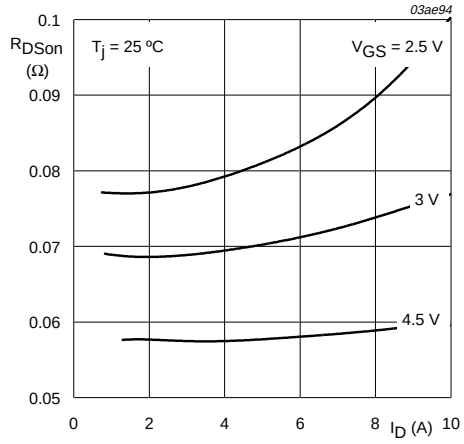
T_j = 25 °C

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values.



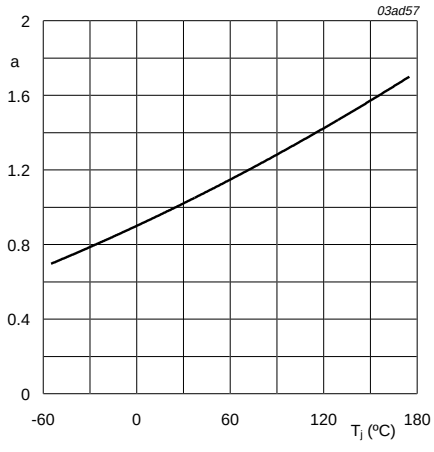
T_j = 25 °C and 150 °C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values.



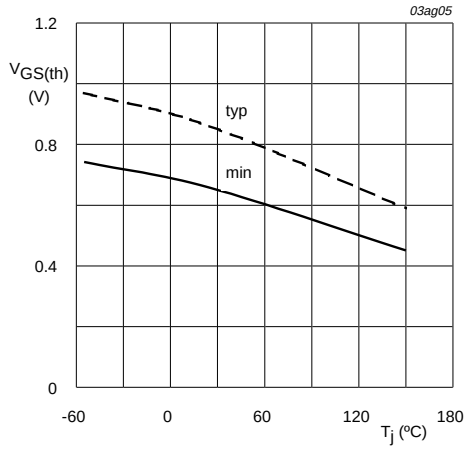
T_j = 25 °C

Fig 7. Drain-source on-state resistance as a function of drain current; typical values.



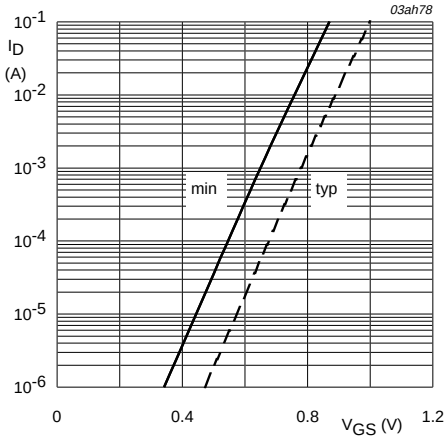
$$a = \frac{R_{DSon}}{R_{DSon(25^\circ C)}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature.



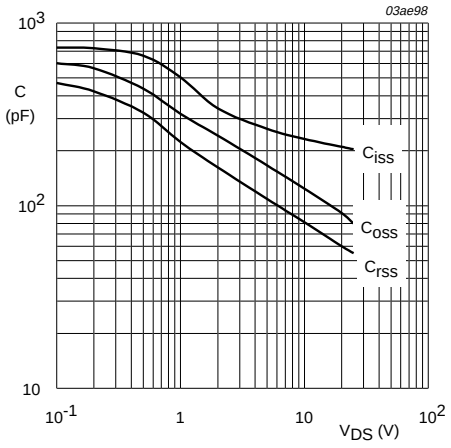
I_D = 1 mA; V_{DS} = V_{GS}

Fig 9. Gate-source threshold voltage as a function of junction temperature.



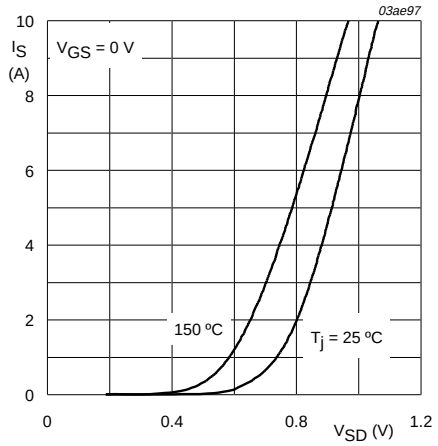
T_j = 25 °C; V_{DS} = 5 V

Fig 10. Sub-threshold drain current as a function of gate-source voltage.



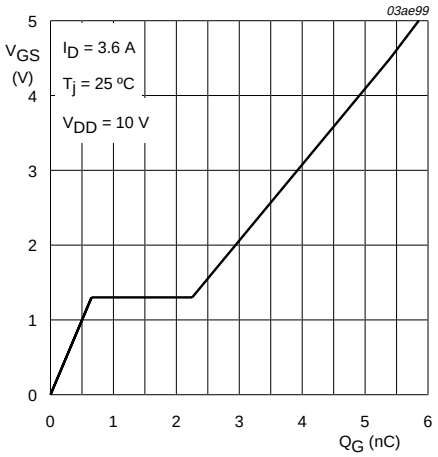
V_{GS} = 0 V; f = 1 MHz

Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.



T_j = 25 °C and 150 °C; V_{GS} = 0 V

Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.

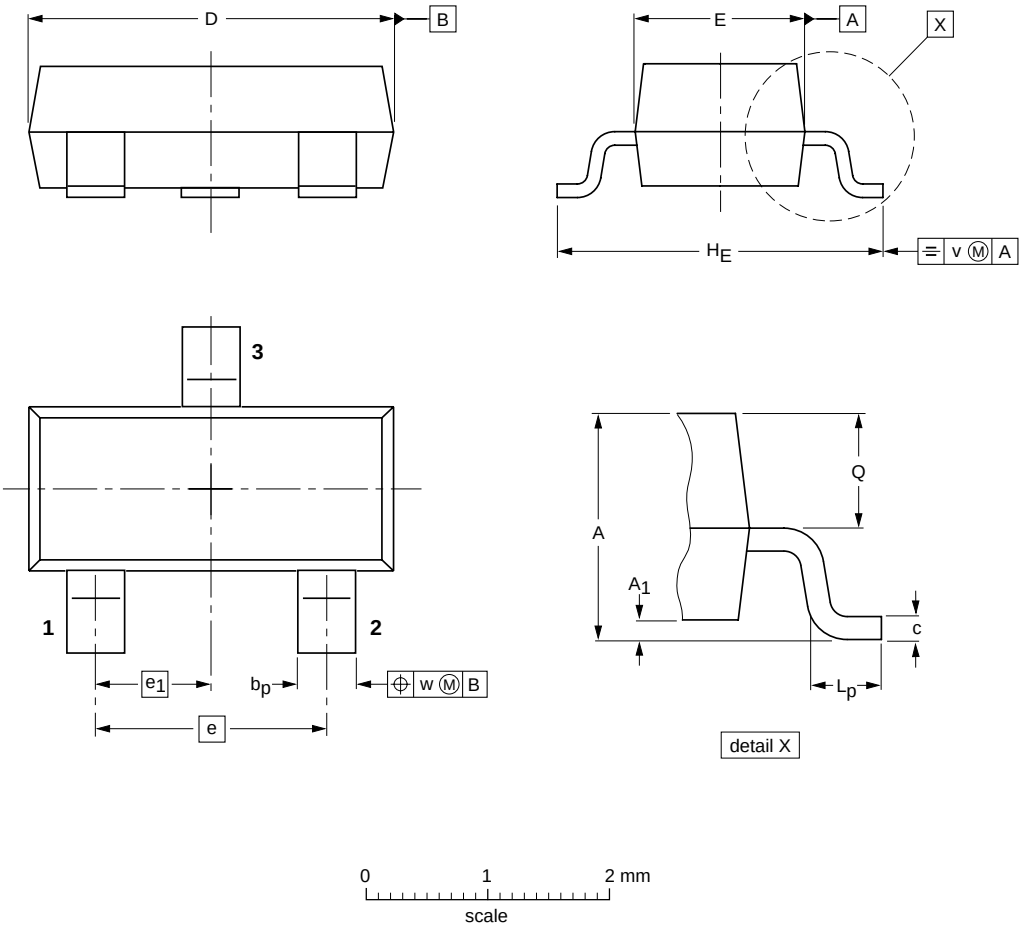


I_D = 3.6 A; V_{DD} = 10 V

Fig 13. Gate-source voltage as a function of gate charge; typical values.

9. Package outline

Plastic surface mounted package; 3 leads **SOT23**



DIMENSIONS (mm are the original dimensions)

UNIT	A	A_1 max.	b_p	c	D	E	e	e_1	H_E	L_p	Q	v	w
mm	1.1 0.9	0.1	0.48 0.38	0.15 0.09	3.0 2.8	1.4 1.2	1.9	0.95	2.5 2.1	0.45 0.15	0.55 0.45	0.2	0.1

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT23		TO-236AB				~~97-02-28~~ 99-09-13

Fig 14. SOT23.

10. Revision history

Table 6: Revision history

Rev	Date	CPCN	Description
02	20011120	-	**Includes product data; second version; supersedes initial version 03 september 2001.** • Table 5 “Characteristics” Correction to $V_{GS(th)}$ conditions. • Figure 9 Correction to curves. • Figure 10 Correction to curves.
01	20010903	-	**Product specification; initial version.**

11. Data sheet status

Data sheet status[1]	Product status[2]	Definition
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Changes will be communicated according to the Customer Product/Process Change Notification (CPCN) procedure SNW-SQ-650A.

[1] Please consult the most recently issued data sheet before initiating or completing a design.

[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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Date of release: 20 November 2001 **Document order number: 9397 750 09107**